

IEEE 1149.4 Mixed-Signal Test Bus Working Group Meeting Minutes

for

March 28th, 2008
8:00 – 10:00 AM

Meeting Agenda:

Time	Topic	Responsibility
8:00 – 10:00 AM	1. Review meeting minutes for March 11 th , 2008	All
	2. Update on ABSDL parser development	All
	3. Review ABSDL/standard documentation	All
	4. Other issues.	All
10:00 AM	Meeting adjourned	Bambang

Meeting Attendees:

Name	Company
Adam Ley	Asset-Intertech
Ken Parker	Agilent Technologies
Heiko Ehrenberg	Goepel Electronics LLC
Adam Cron	Synopsys
Steve Sunter	Logicvision
Bambang Suparjo	Mentor Graphics

1. Review meeting minutes for March 11th, 2008.

The meeting minutes for March 11th, 2008 have been approved, suggested by Adam Cron and seconded by Ken.

2. Update on ABSDL parser development

- a. The parser gives error messages on the updated BSDL file for STA400 prepared by Bambang. The results have been sent to Heiko to be reviewed. Heiko and his team will also review the parser.
- b. The initial version of the parser has been sent to TI group.

3. Review Standard Draft

- a. Issue on Rcom

- i. The new diagram for Figure 39 proposed by Adam Cron has been reviewed.
 - Steve commented that the new diagram provides better clarification on connection that associated to Rcom.
 - R_{S1} , R_{S2} and R_{PROT} are all related to protection circuitry. It is suggested to change the resistance names.
 - Highlight only the paths associated to AB1, AB2 and the pin/pad.
 - Adam Cron will update the diagram. The group will review again the diagram and the associated description.

 - ii. The updated diagram for Figure 53 proposed by Adam has been reviewed as well.
 - ABM switches are attached at each core I/O to provide better clarification.
 - R6 is missing.
 - The group was focusing the discussion on network associated to R3, to identify any possibility to minimize the effect of this resistance in testing the external network. Although R3 can be considered as residual element but it might be good to provide recommendation to minimize its effect in testing. Adam Ley suggested placing AB2 switch close to the external pin of R3 connection so that the value of R3 will not affect the test measurement. Adam Cron will update the diagram to be reviewed by the group.
- b. The items in the review list that have been addressed/fixed are shown below:
- i. Item #4 – Claus 6.2.2 on issue related to description for pattern P0 - Recommendation 6.2.1.2 a).
 - ii. Item #5 – Clause 9.5.2.2 on incorrect Figure 43.
 - iii. Item #6 – Clause 9.5.2.7 on incorrect Figure 48 and Figure 49.
 - iv. Item #8 – Clause 9.2 on Rsw1 (**needs to be validated**).
 - v. Item #9 – Clause 10.4.5 on MST_TBIC example syntax.

4. Other issues

The next meeting will be on April 8th, 2008 at 8 AM PDT.

5. The meeting adjourned at 10:00 AM PDT